



Docket No.: 63979-033

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of :
Yoshihiko KANZAWA, et al. :
Application No.: 10/674,523 : Group Art Unit: 2858
Filed: October 01, 2003 : Examiner:
For: METHOD FOR MEASURING SEMICONDUCTOR CONSTITUENT ELEMENT
CONTENT AND METHOD FOR MANUFACTURING A SEMICONDUCTOR
DEVICE (As amended)

PRELIMINARY AMENDMENT

Mail Stop Preliminary Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Prior to examination of the above-referenced application, please amend the application as follows:

IN THE SPECIFICATION:

Please amend the title as follows:

~~SPECIFICATION~~ METHOD FOR MEASURING SEMICONDUCTOR CONSTITUENT
ELEMENT CONTENT AND METHOD FOR MANUFACTURING A SEMICONDUCTOR
DEVICE